



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Inventor Joonhyung Kwon Filing Date December 29, 2003  
Art Unit 2856 Examiner LARKIN, Daniel  
Title: Scanning Probe Microscope With Improved Probe Tip Mount  
Docket No.: PSI004-1C US Application No. 10/748,827

**Santa Clara, California**

Mail Stop AMENDMENT  
COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, VA 22313-1450

## AMENDMENT

Dear Sir:

This amendment is in response to the Office Action dated November 1, 2004.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 3 of this paper.

**Amendments to the Drawings** begin on page 8 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

**Remarks/Arguments** begin on page 9 of this paper.

An Appendix of one sheet which includes amended drawing figures is attached, following page 13 of this paper.

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